

Search Notes

Application/Control No.

10/710,452

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

YANG ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	745	7/19/2005	BT
438	747	7/19/2005	BT
438	754	7/19/2005	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search keywords and inventors' name using USPAT, USPG-PUG, JPO, EPO	7/19/2005	BT